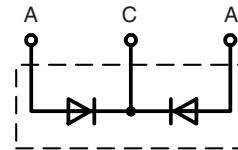


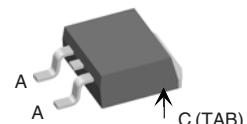
HiPerFRED™ Epitaxial Diode with common cathode and soft recovery

I_{FAV} = 2x10 A
V_{RRM} = 1200 V
t_{rr} = 40 ns

V _{RSM} V	V _{RRM} V	Type
1200	1200	DSEC 16-12AS



TO-263 AB



A = Anode, C/TAB = Cathode

Symbol	Conditions	Maximum Ratings		Features
I _{FRMS}		14	A	
I _{FAVM}	T _C = 115°C; rectangular, d = 0.5	10	A	
I _{FSM}	T _{VJ} = 45°C; t _p = 10 ms (50 Hz), sine	40	A	
E _{AS}	T _{VJ} = 25°C; non-repetitive I _{AS} = 8 A; L = 180 µH	6.9	mJ	
I _{AR}	V _A = 1.25·V _R typ.; f = 10 kHz; repetitive	0.8	A	
T _{VJ}		-55...+175	°C	
T _{VJM}		175	°C	
T _{stg}		-55...+150	°C	
P _{tot}	T _C = 25°C	60	W	
F _c	mounting force	20...60	N	
Weight	typical	2	g	

Symbol	Conditions	Characteristic Values		Advantages
		typ.	max.	
I _R *	T _{VJ} = 25°C V _R = V _{RRM} T _{VJ} = 150°C V _R = V _{RRM}	60 0.25	µA mA	
V _F *	I _F = 10 A; T _{VJ} = 150°C T _{VJ} = 25°C	1.96 2.94	V	
R _{thJC} R _{thCH}		0.5	2.5 K/W K/W	
t _{rr}	I _F = 1 A; -di/dt = 50 A/µs; V _R = 30 V; T _{VJ} = 25°C	40	ns	
I _{RM}	V _R = 100 V; I _F = 12 A; -di _F /dt = 100 A/µs T _{VJ} = 100°C	8.5	A	

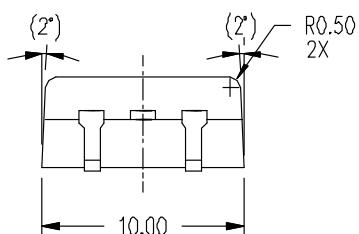
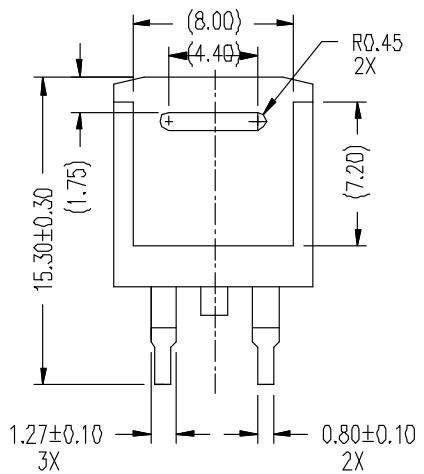
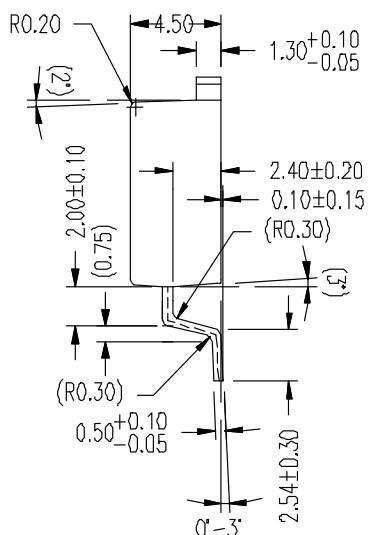
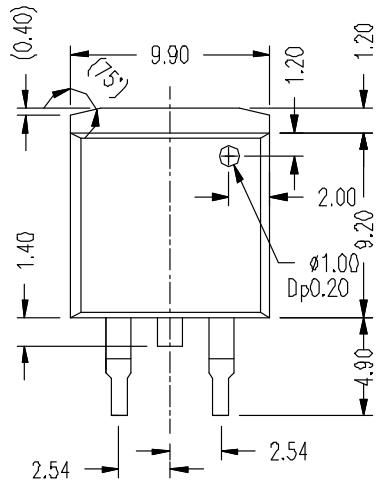
Pulse test: * Pulse Width = 5 ms, Duty Cycle < 2.0%
* Pulse Width = 300 µs, Duty Cycle < 2.0%

Data according to IEC 60747 and per diode unless otherwise specified

Advantages

- Avalanche voltage rated for reliable operation
- Soft reverse recovery for low EMI/RFI
- Low I_{RM} reduces:
 - Power dissipation within the diode
 - Turn-on loss in the commuting switch

Dimensions see Outlines.pdf



NOTE:

1. These dimensions do not include mold protusion.
2. () is reference dimension only.

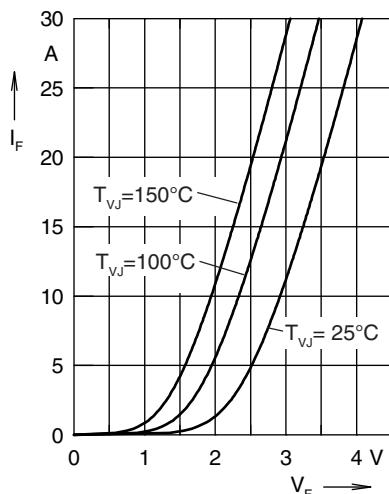
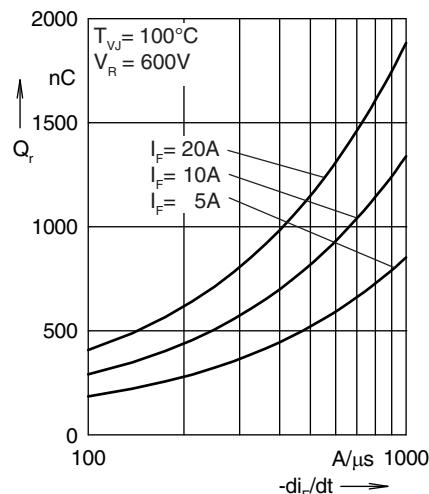
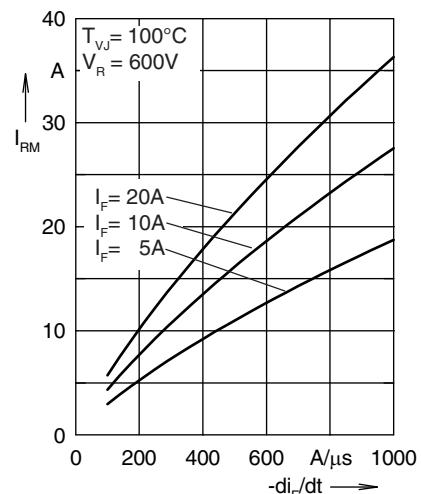
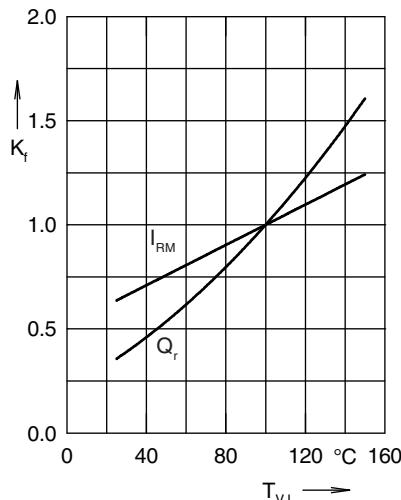
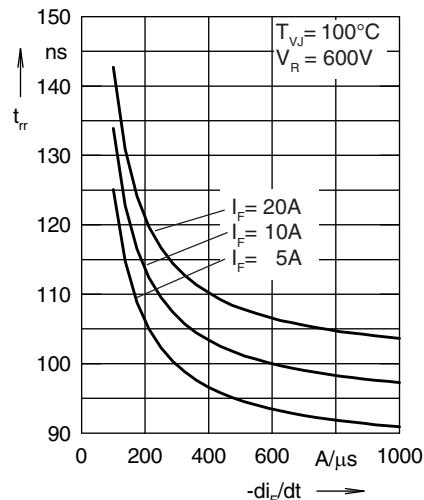
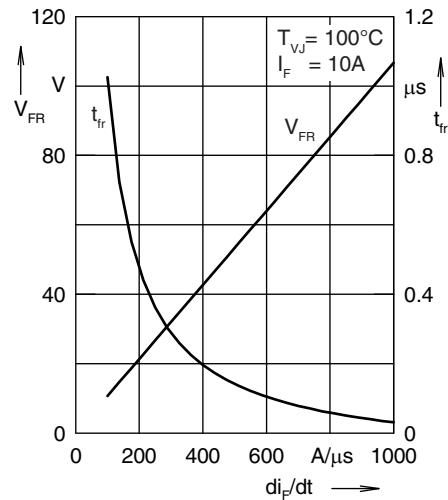
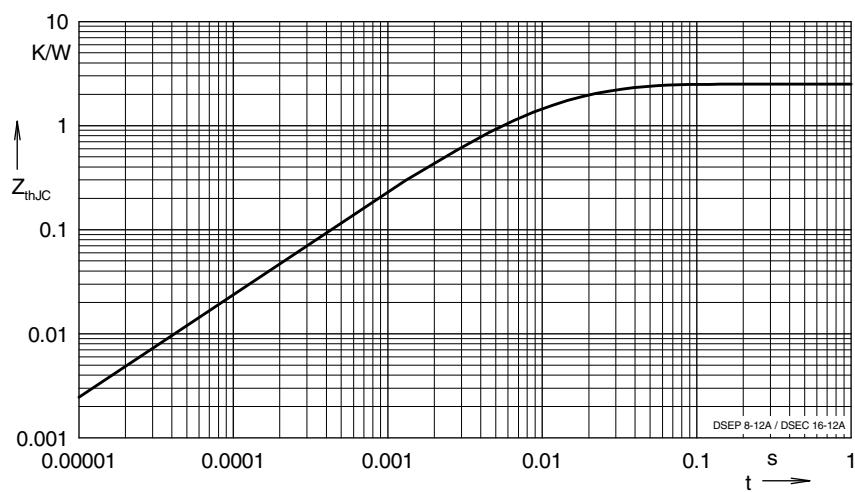
Fig. 1 Forward current I_F versus V_F Fig. 2 Reverse recovery charge Q_r versus $-di_F/dt$ Fig. 3 Peak reverse current I_{RM} versus $-di_F/dt$ Fig. 4 Dynamic parameters Q_r , I_{RM} versus T_{VJ} Fig. 5 Recovery time t_{rr} versus $-di_F/dt$ Fig. 6 Peak forward voltage V_{FR} and t_{fr} versus di_F/dt 

Fig. 7 Transient thermal resistance junction to case

Constants for Z_{thJC} calculation:

i	R_{thi} (K/W)	t_i (s)
1	1.449	0.0052
2	0.558	0.0003
3	0.493	0.017